



ASIAN TEST SYMPOSIUM (ATS) 2011

NEW DELHI, INDIA

November 21-23, 2011

The Asian Test Symposium (ATS) 2011 is the twentieth in this series of symposia started in 1992 devoted to testing, fault tolerant computing and the design of reliable circuits and systems. ATS is recognized as the main event in Asia that covers the many dimensions of testing and fault tolerance. The 2011 edition of ATS will be held in NEW DELHI, INDIA. Inspired by the fact that technology is trending towards extremely high levels of integration at the package and chip levels, coupled with the very high speeds of operation and use of deeply scaled technology, the theme for ATS 2011 will be *Test Odyssey 2020: Testing Systems and Devices at the Peta and Nano Scales*.

Technical Paper Submissions: Original contributions in testing, fault tolerant and reliable computing are solicited. Topics of interest include, but are not limited to, the following categories:

<i>Automatic Test Pattern Generation (ATPG)</i>	<i>Boundary Scan</i>
<i>Test Compression</i>	<i>Online Test</i>
<i>Temperature/Power-aware Test</i>	<i>Design-for-testability (DFT)</i>
<i>Microprocessor Test</i>	<i>Mixed signal and Analog Test</i>
<i>Memory Test</i>	<i>System-in-package (SiP)/ 3D Test</i>
<i>Test Quality and Reliability</i>	<i>Design Validation/Silicon Debug</i>
<i>Fault Modeling/Defect Based Test</i>	<i>Fault Simulation/Diagnosis</i>
<i>Software Testing</i>	<i>Board and System Test</i>
<i>Innovative Industrial Test Practices*</i>	<i>Other</i>

In above list of categories, ATS 2011 has introduced a new category for technical papers to solicit original contributions that showcase *Innovative Industrial Test Practices*. Submissions could be related to silicon test data studies, new/novel test EDA tool user experiences, or case studies. Submission requirements and review guidelines for these papers are the same as regular technical papers.

Submissions should be full-length papers (double-column format, font size at least 10pt, length 6 to 10 pages), including all illustrations, tables, references. **Submission deadline is May 27, 2011.** More information on technical paper submission to ATS 2011 can be found at the conference website.

Special Session Submissions: ATS 2011 encourages test practitioners from academia and industry to submit proposals on state-of-the-art topics in the domain. Proposals related to *panels/special sessions, embedded tutorials, and full/half day tutorials* are now solicited.

Proposals can be upto 3 pages, and should detail abstract and bulleted list of topics, targeted audience, proposed duration, organizer's name and affiliation, speakers' names, affiliations, short bios, and approval status for participation at ATS 2011. **Submission deadline is June 3, 2011.** More information on special session submissions to ATS 2011 can be found at the conference website.

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